

PM080P150CG

-150V -50A 80mΩ Si Single P-ch Enhancement Mode MOSFET with Normal Diode

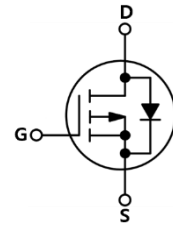
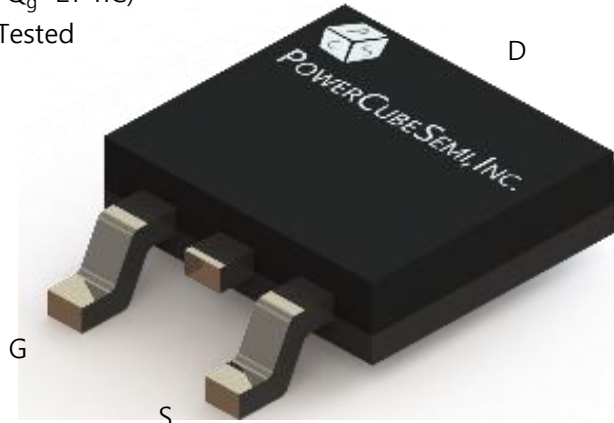
Features

Si P-Ch Enhancement Mode Power MOSFET

- Rated to -150V at -50Amps @ $T_j = 25^\circ\text{C}$
- Max $R_{DS(on)} = 80\text{ m}\Omega$
- Typ $R_{DS(on)} = 65\text{ m}\Omega$
- Gate Charge(Typ. $Q_g=27\text{ nC}$)
- 100% Avalanche Tested

Application

- Power switch
- DC/DC converters



PKG type : TO-252 (DPAK)

Description

The PM080P150CG uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.

Absolute Maximum Ratings

Symbol	Parameter	Test Condition	Value	Unit
BV_{DSS}	Drain-source breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-150	V
I_D	Drain current	$T_c=25^\circ\text{C}$	-50	A
I_{DM}	Drain current	Pulse width limited by junction temperature	-200	A
V_{GS}	Gate-source voltage		± 20	V
E_{AS}	Single pulsed avalanche energy	$V_{GS}=-10V, R_G=25\Omega$ $V_{DD}=-50V, L=0.5mH$	132	mJ
P_d	Power dissipation	$T_c=25^\circ\text{C}$	96	W
T_j	Operating junction		150	$^\circ\text{C}$
T_{stg}	Storage temperature		-55 to 150	$^\circ\text{C}$

Package Marking and Ordering Information

Device Marking	Device	Package	Packing Method	Tape width	Quantity
PM080P150CG	PM080P150	TO-252	REEL	-	2500

Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical			Unit
			Min	Typ.	Max.	
BV_{DSS}	Drain-source breakdown voltage	$V_{GS} = 0V, I_D = -250\mu A, T_J = 25^\circ C$	-150	-	-	V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = -150V, V_{GS} = 0V$	-	-	-1	μA
I_{GSS}	Gate-source leakage current	$V_{GS} = \pm 20V$	-	-	± 100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1	-2.5	-4	V
$R_{DS(ON)}$	Static drain-source on state resistance	$V_{GS} = -10V, I_D = -5A$	-	65	80	m Ω
g_{FS}	Forward transconductance	$V_{DS} = -5V, I_D = -5A$	-	9	-	S
$t_{d(on)}$	Turn-on Delay time	$V_{DD} = -75V, I_D = -5A, R_G = 3\Omega$	-	9	-	ns
t_r	Turn-on Rise time		-	10	-	
$t_{d(off)}$	Turn-off Delay time		-	29	-	
t_f	Turn-off Fall time		-	4	-	



Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$R_{\theta JC}$	Thermal resistance, Junction to case		1.3	-	$^{\circ}\text{C}/\text{W}$
C_{iss}	Input capacitance	$V_{DS} = -75\text{V}, V_{GS} = 0\text{V},$ $f = 1.0\text{MHz}$	3918	-	pF
C_{oss}	Output capacitance		149	-	
C_{rss}	Reverse transfer capacitance		106	-	
$Q_{g(\text{tot})}$	Total gate charge at 10V	$V_{DD} = -75\text{V}, I_D = -5\text{A}$ $V_{GS} = -4.5\text{V}$	27	-	nC
Q_{gs}	Gate to source gate charge		7	-	
Q_{gd}	Gate to drain "Miller" charge		3	-	

Electrical Characteristics of Si Diode

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
I_S	Maximum continuous drain to source diode forward current	$T_c = 25^{\circ}\text{C}$	-	-50	A
V_{SD}	Drain to source diode forward voltage	$I_{SD} = -5\text{A}, V_{GS} = 0\text{V}$	-	-1.2	V
T_{rr}	Reverse recovery time	$I_F = -5\text{A}, V_{GS} = 0\text{V},$ $di_F/dt = -500\text{A}/\mu\text{s}$	51	-	ns
Q_{rr}	Reverse recovery charge		434	-	nC

Typical Characteristics

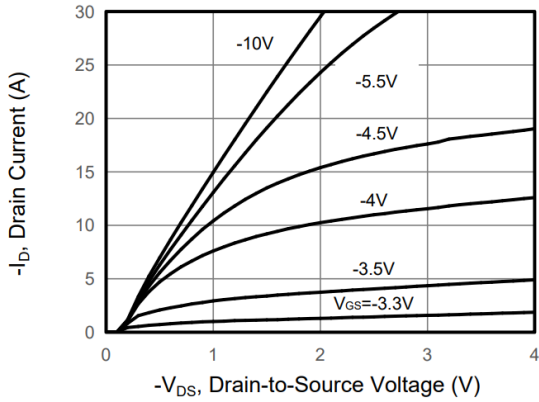


Figure 1. Output Characteristics

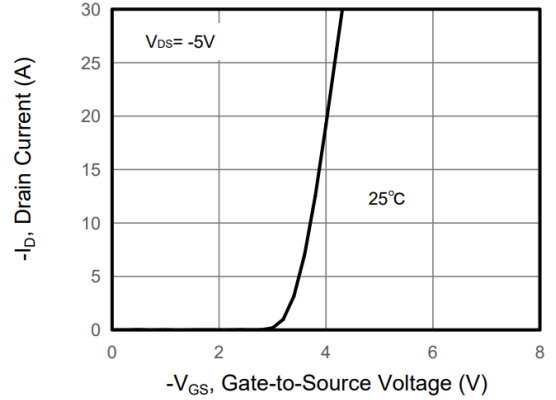


Figure 2. Transfer Characteristics

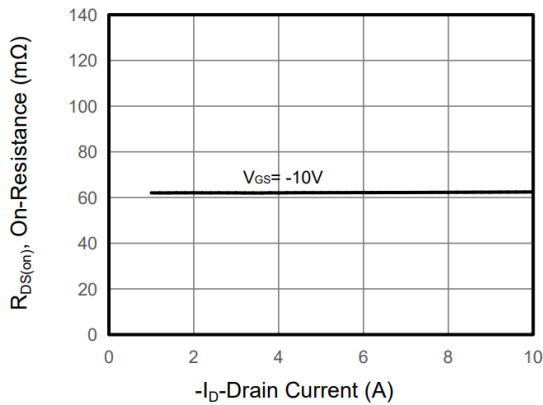


Figure 3. Drain Source On Resistance

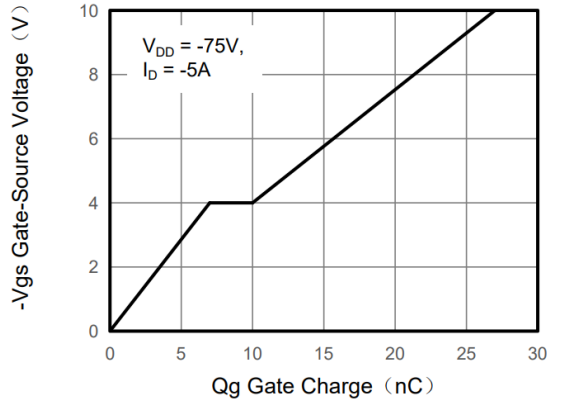


Figure 4. Gate Charge

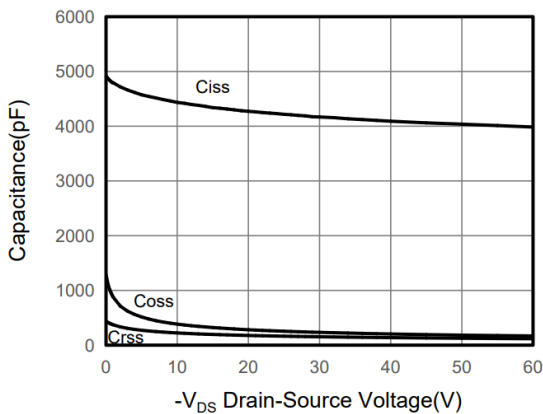


Figure 5. Capacitance

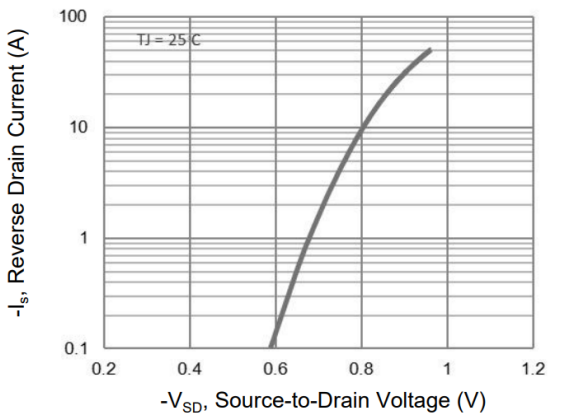


Figure 6. Source-Drain Diode Forward

Typical Characteristics

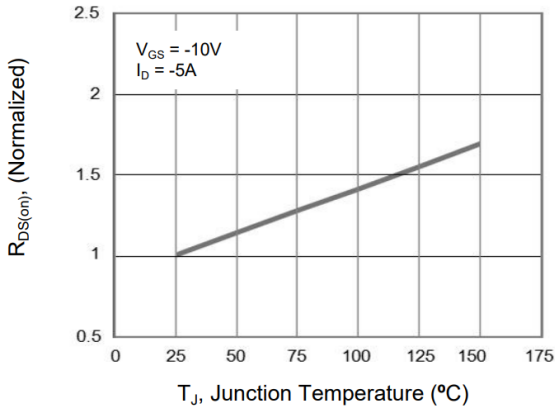


Figure 7. Drain-Source On-Resistance

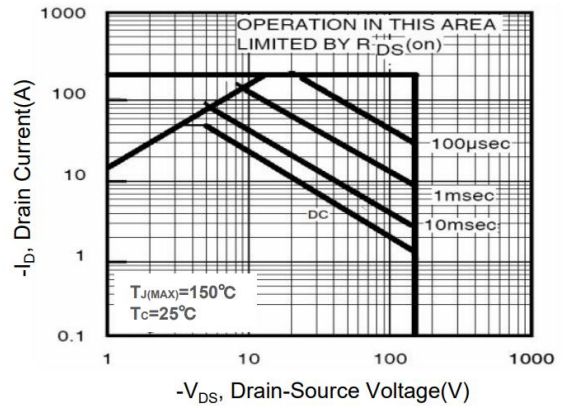


Figure 8. Safe Operation Area

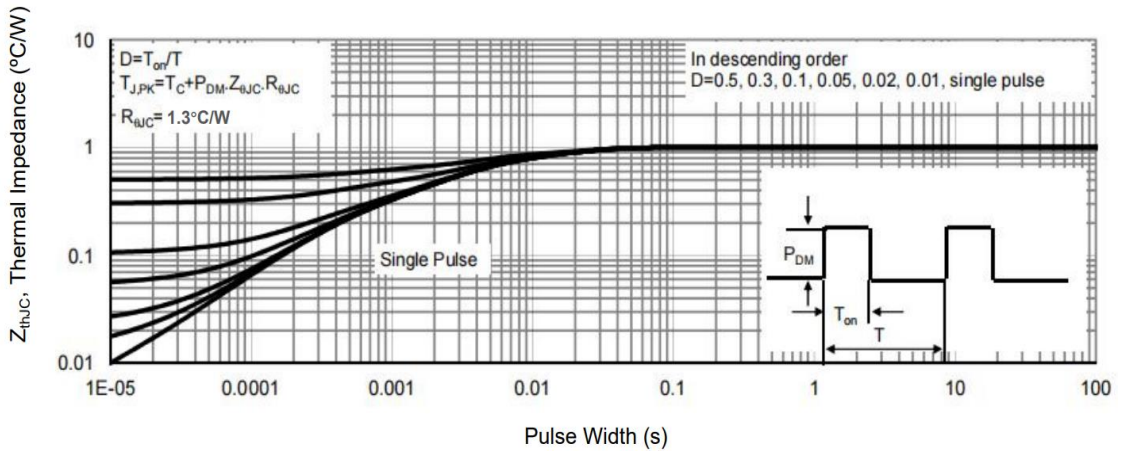
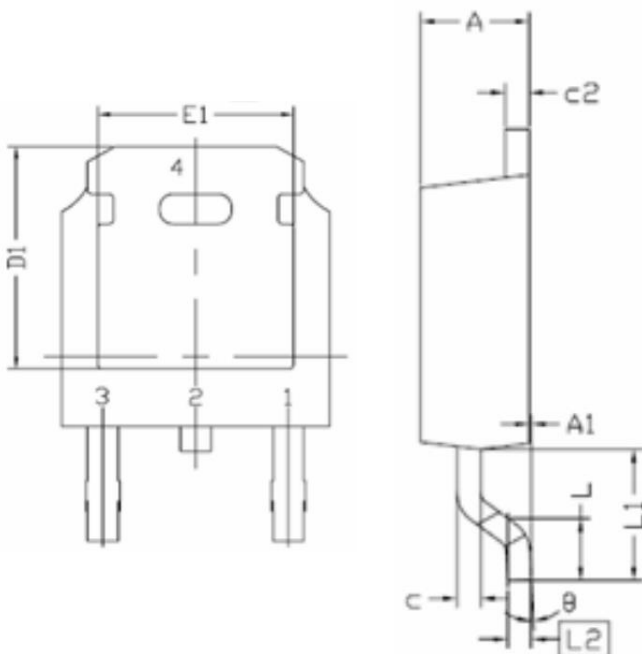
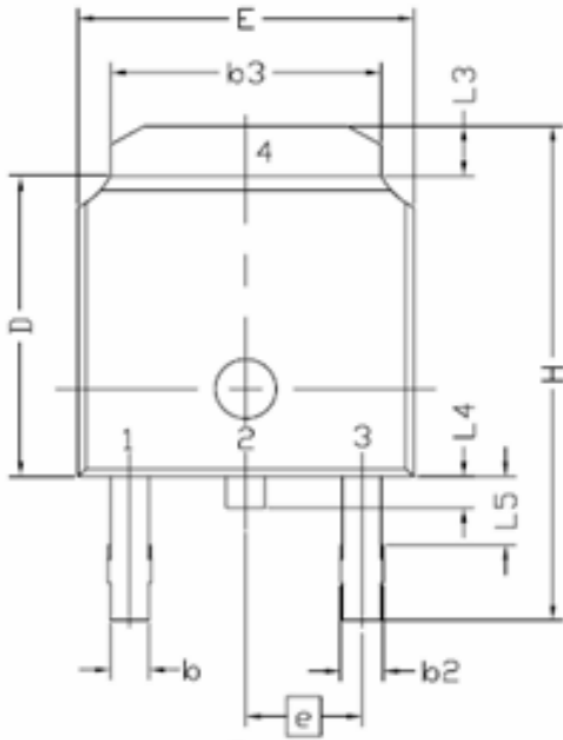


Figure 9. Normalized Maximum Transient Thermal Impedance

Package Outline

Unit : mm



SYMBOL	DIMENSIONS		
	MIN	NOM	MAX
E	6.34	6.54	6.74
L	1.30	1.60	1.90
L1	2.60	2.90	3.20
L2	0.5 BSC		
L3	0.82	1.02	1.22
L4	0.80	1.00	1.20
L5	2.60	2.90	3.20
D	5.80	6.10	6.40
H	8.40	9.00	9.60
b	1.42	1.52	1.62
b2	2.35	2.55	2.75
b3	5.20	5.30	5.40
e	4.58 BSC		
A	2.08	2.28	2.48
A1	0.00	0.15	-
c	0.40	0.50	0.60
c2	0.40	0.50	0.60
D1	-	5.25	-
E1	-	4.8	-
θ	0.00°	10.00°	